AMENDMENTS

Please amend the claims as indicated hereafter.

1. (Original) A method for configuring solid-state storage devices, comprising:

providing a solid-state storage device;

analyzing an error rate of said solid-state storage device; and

selecting, based on said error rate, an error correction code power level to provide said solid-state storage device with a pre-determined error rate.

2. (Currently Amended) The method of claim 1, wherein said analyzing said error rate of said solid-state storage device further comprises:

testing said solid-state storage device for defects;

determining said error rate of said solid-state storage device based on said testing; and

comparing said error rate of said solid-state storage device to said pre-determined error rate.

3. (Original) The method of claim 2, wherein said testing further comprises performing a write-read-compare operation on at least one selected cell.

4. (Original) The method of claim 1, further comprising analyzing an intended user application of said solid-state storage device, wherein said selecting is further based on said intended user application.

5. (Original) The method of claim 1, wherein said selecting further comprises switching a selector lever to select a desired error correction code.

6. (Original) The method of claim 1, wherein said solid-state storage device comprises a plurality of magnetoresistive storage cells.

7. (Original) The method of claim 1, further comprising determining a rate of deterioration of said storage device, wherein said selecting is further based on said rate of deterioration.

8. (Currently Amended) A method for configuring solid-state storage devices, comprising:

determining a value indicative of an error rate for a solid-state storage device;

selecting ~~a set of~~ an error correction code based on said value; and

installing said selected ~~set of~~ error correction code in said solid-state storage device.

9. (Original) The method of claim 8, wherein said selecting is further based on an intended application for said solid-state storage device.

10. (Original) The method of claim 8, further comprising comparing said value to a pre-determined threshold, wherein said selecting is based on said comparing.

11. (Original) The method of claim 8, further comprising:

determining a value indicative of a rate of deterioration of said storage device; and

comparing, to a threshold, said value indicative of said rate of deterioration,

wherein said selecting is based on said comparing.

12. (Currently Amended) A system for configuring solid-state storage devices,

comprising:

a solid-state storage device; and

an error correction code (ECC) selection system configured to automatically select a set of

an error correction code based on an error rate of said storage device, said ECC selection system

further configured to install said selected set of error correction code in said solid-state storage

device.

13. (Currently Amended) The system of claim 12, wherein said ECC selection system is

further configured to receive information indicative of an intended application for said storage

device and to select said set of error correction code based on said information.

14. (Original) The system of claim 12, wherein said ECC selection system is configured

to determine a value indicative of said error rate and to compare said value to a pre-determined

threshold.

15. (Currently Amended) The system of claim 12, wherein said ECC selection system is

configured to select said set of error correction code based on a rate of deterioration of said

storage device.

16. (Currently Amended) A computer-readable medium having ~~an error correction code~~ ~~selection system for use with a solid-state storage device~~ <u>a program capable of being executed by</u> <u>an instruction execution system</u>, said ~~computer-readable medium~~ <u>program</u> comprising:

logic configured to receive information corresponding to ~~said~~ <u>a</u> solid-state storage device;

logic configured to analyze said information corresponding to said solid-state storage device; and

logic configured to select ~~a set of~~ <u>an</u> error correction code for use with said solid-state storage device based on said information received corresponding to said solid-state storage device.

17. (Original) The computer-readable medium of claim 16, wherein said information is indicative of an error rate for said storage device.

18. (Original) The computer-readable medium of claim 17, wherein said information is further indicative of an intended application for said storage device.

19. (Original) The computer-readable medium of claim 18, wherein said information is further indicative of a rate of deterioration for said storage device.

20. (Currently Amended) A system for configuring solid-state storage devices, comprising:

means for testing a solid-state storage device and for determining a value indicative of an error rate for said storage device;

means for comparing said value to a pre-determined threshold;

means for selecting ~~a set of~~ an error correction code based on said comparing means; and

means for installing said selected ~~set of~~ error correction code in said storage device.

21. (Original) The system of claim 20, wherein said selecting means is further configured to select said error correction code based on an intended application for said storage device.

22. (Original) The system of claim 20, wherein said selecting means is further configured to select said error correction code based on a rate of deterioration for said storage device.